

The MSV-5000 series is a microscopic spectrophotometer system providing transmittance/reflectance measurements of a microscopic sample area with a wide wavelength range from ultraviolet to near infrared. A broad range of applications including the collection of transmittance/reflectance spectra of a sample, measurement of the band gap and film thickness of semiconductors, evaluation of the optical characteristics of functional crystals and the color analysis of microscopic samples can be easily implemented using the MSV-5000 series.

Wide spectral measurement range

The microscope system utilizes wide-band cassegrain objectives to provide transmittance/reflectance measurements continuously from 200 to 2700 nm (MSV-5200).

Polarization measurement

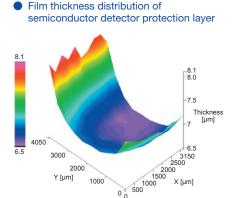
An automated Glan-Taylor polarizer system (standard) provides polarization measurements in combination with the optional automated polarization analyzer.

Auto XYZ stage

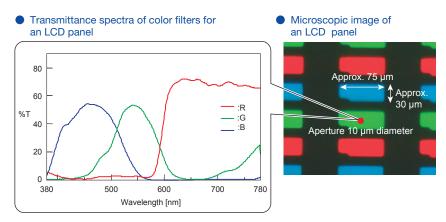
The optional automated stage enhances the operation performance of the system especially for mapping and multi-point measurements.

JASCO Spectra Manager™ II

Spectra Manager™ II software, a cross-platform control and analysis package for all JASCO spectroscopic instruments, offers quick and easy data acquisition and analysis.



The film thickness distribution of semiconductor detector protection layer was calculated from interference wave shape in NIR region.



A circular 10 μm aperture was applied for each subpixel of red, green and blue (R, G, B).

Specifications

Model:	MSV-5100	MSV-5200	MSV-5300	
Optical system:	Double beam single monochromator Czerny-Turner mount			
Light source:	30W Deuterium lamp, 20W Halogen lamp			
Light source (option):	150W Xenon lamp (air-cooled)			
Wavelength range:	200 - 900 nm	200 - 2700 nm	200 - 1600 nm	
Wavelength accuracy:	± 0.3 nm (656.1 nm)	± 0.3 nm (656.1 nm) ± 1.5 nm (1312.2 nm)		
Spectral bandwidth:	1, 2, 5, 10, L2, L5, L10 nm	1, 2, 5, 10, L2, L5, L10 nm (UV/Vis) 4, 8, 20, 40, L8, L20, L40 nm (NIR)	1, 2, 5, 10, L2, L5, L10 nm (UV/Vis) 2, 4, 10, 20, L4, L10, L20 nm (NIR)	
Scan modes:	Continuous scan, step scan			
Detector:	PMT	PMT Peltier-cooled PbS	PMT Peltier-cooled InGaAs	
Sample observation:	High resolution CMOS camera (1600 × 1200 pixel), optical zoom, ATOS feature, LED illumination			
Sample observation (option):	Binocular, polarized observation, objective lens			
Objective:	Cassegrain objective, ×10, ×16, ×32 selectable *1			
Condenser mirror:	Cassegrain collection mirror, ×10, ×16, ×32 user-interchangeable *1 (Automated condenser mirror compensation function)			
Aperture:	User-selectable dual-aperture settings for circular and rectangular (slit type) apertures 10, 20, 30, 50, 100, 200 μmφ (×16 objective) 5, 10, 15, 25, 50, 100 μmφ (×32 objectibe) 16, 32, 48, 80, 160, 320 μmφ (×10 objective)			
Sample stage:	Manual stage (working area: X 50 × Y 75 × Z 20 mm) *2			
Sample stage (option):	Auto stage (working area: X 76 × Y 52 × Z 25 mm, 1 μm step) *2, joystick (option)			
Polarizer:	Glan-Taylor, automatic insertion/angle setting			
Analyzer (option):	Glan-Taylor, automatic insertion/angle setting			
Control panel:	Cassegrain switching and indicator, transmittance/reflectance mode indicator, aperture selection, measurement start/stop, auto focus, automatic condenser mirror compensation, optical zoom, automated sample illumination, sample compartment illumination ON/OFF, ATOS illumination ON/OFF			
Dimensions:	700 (W) × 740 (D) × 640 (H) mm			
Weight:	105 kg			
Power requirement:	150 VA			
Software:	JASCO Spectra Manager™ II			
OS:	Windows7 Professional			
Program:	Microscope Measurement (multi-point measurement, line and lattice mapping), Micro Spectra Analysis, Spectra Analysis (data processing such as film thickness calculation, color calculation, peak detection, derivatives), Time-Course Measurement, Validation, JASCO Canvas, Administrative Tools			
Program (option) *3	Fixed wavelength mapping (line and lattice mode), auto focus, multi-image			

- *1. Cassegrain objective and cassegraing collection mirror are provided with the same magnification.
- *2. The moving distance of the condensor mirror and the objective magnification depends upon the sample.
- *3. Optional programs are provided when auto stage is selected.



• Specifications are subject to change without notice.

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